

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Patent Application Serial No. .... 09/730,335  
 Filing Date ..... December 4, 2000  
 Inventor ..... Charles H. Dennison  
 Assignee ..... Micron Technology, Inc.  
 Group Art Unit ..... 2811  
 Examiner ..... Ori Nadav  
 Attorney Docket No. .... MI22-1577  
 Customer No. .... 021567  
 Title ..... Field Effect Transistors and Integrated Circuitry

**SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT**

References -- See Attached Form PTO-1449

The attached form PTO-1449 is submitted in compliance with 37 CFR §1.56. Copies of the cited art are included. No admission is made regarding whether all the submitted references are prior art.

Respectfully submitted,

Dated: 11-14-03


By:   
 Mark S. Matkin  
 Reg. No. 32,268

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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1577		SERIAL NO. 09/730,335	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT: Charles H. Dennison			
				FILING DATE December 4, 2000		GROUP 2811	
U.S. PATENT DOCUMENTS							
Examiner's Initials		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	5,923,999	07/13/99	Balasubramanyam et al.			
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
	AJ	JP63012132	01/19/88	Japan (Sumi et al.)			Abstract
	AK	JP63012152	01/19/88	Japan (Tsukamoto et al.)			Abstract
	AL	JP8017758	01/19/96	Japan (Tawara)			Abstract & machine
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AM						
	AN						
	AO						
EXAMINER		DATE CONSIDERED					
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U.S. PATENT DOCUMENTS							
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	AA						
	AB						
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	AD						
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	AH						
	AI						

FOREIGN PATENT DOCUMENTS							
	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
	AJ JP8279553	10/22/96	Japan (Fujiwara)			Abstract & machine	
	AK JP10093077	04/10/98	Japan (Tsukamoto)			Abstract & machine	
	AL						

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)		
	AM	
	AN	
	AO	

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U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.  
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APPLICANT: Charles H. Dennison

FILING DATE  
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2811

## U.S. PATENT DOCUMENTS

Examiner's Initials	Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
	AA	5,696,017	12/9/97	Ueno		
	AB	6,357,909 B1	3/25/03	Lin, et al.		
	AC					
	AD					
	AE					
	AF					
	AG					
	AH					
	AI					

## FOREIGN PATENT DOCUMENTS

	Document Number	Date	Country	Class	Subclass	Translation
						Yes No
	AJ					
	AK					
	AL					

## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

	AM	J. Nulman, B. Cohen, and K. Ngan, "Titanium Silicide and Titanium Nitride Layers Formed in an integrated Multichamber System", Proc. VMI/C Conference (1991), pp. 312-315.
	AN	William C. O'Mara, Robert B. Herring, and Lee p. Hunt, "Handbook of Semiconductor Silicon Technology", Noyes Publ., Norwich, New York (1990), p. 684.
EXAMINER	DATE CONSIDERED	

\*EXAMINER. Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant